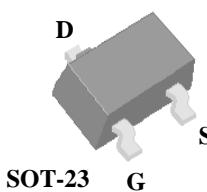




- ▼ Simple Drive Requirement
- ▼ Small Package Outline
- ▼ Surface Mount Device

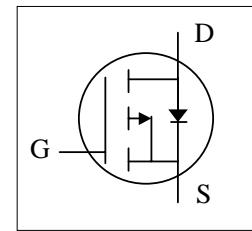


BV_{DSS}	-20V
$R_{DS(ON)}$	65mΩ
I_D	- 4.2A

Description

Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, low on-resistance and cost-effectiveness.

The SOT-23 package is widely preferred for commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	- 20	V
V_{GS}	Gate-Source Voltage	± 12	V
$I_D @ T_A = 25^\circ C$	Continuous Drain Current ³	-4.2	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current ³	-3.4	A
I_{DM}	Pulsed Drain Current ¹	-10	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation	1.38	W
	Linear Derating Factor	0.01	W/°C
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Unit
$R_{thj-amb}$	Maximum Thermal Resistance, Junction-ambient ³	90	°C/W



AP2305GN

Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-20	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-4.5\text{A}$	-	-	53	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-4.2\text{A}$	-	-	65	$\text{m}\Omega$
		$V_{\text{GS}}=-2.5\text{V}, I_{\text{D}}=-2.0\text{A}$	-	-	100	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-0.5	-	-1.16	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=-5\text{V}, I_{\text{D}}=-4\text{A}$	-	14	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=-20\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-1	uA
	Drain-Source Leakage Current ($T_j=55^\circ\text{C}$)	$V_{\text{DS}}=-16\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-10	uA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 12\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_{\text{D}}=-4\text{A}$	-	13	21	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=-16\text{V}$	-	1.4	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=-4.5\text{V}$	-	4	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ²	$V_{\text{DS}}=-10\text{V}$	-	8	-	ns
t_r	Rise Time	$I_{\text{D}}=-1\text{A}$	-	17	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=3.3\Omega, V_{\text{GS}}=-5\text{V}$	-	24	-	ns
t_f	Fall Time	$R_D=10\Omega$	-	33	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	920	1470	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=-20\text{V}$	-	90	-	pF
C_{rss}	Reverse Transfer Capacitance	$f=1.0\text{MHz}$	-	85	-	pF
R_g	Gate Resistance	$f=1.0\text{MHz}$	-	4.5	6.8	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_S=-1.2\text{A}, V_{\text{GS}}=0\text{V}$	-	-	-1.2	V
trr	Reverse Recovery Time ²	$I_S=-4\text{A}, V_{\text{GS}}=0\text{V},$ $dI/dt=100\text{A}/\mu\text{s}$	-	27	-	ns
Qrr	Reverse Recovery Charge		-	14	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in² copper pad of FR4 board ; $270^\circ\text{C}/\text{W}$ when mounted on min. copper pad.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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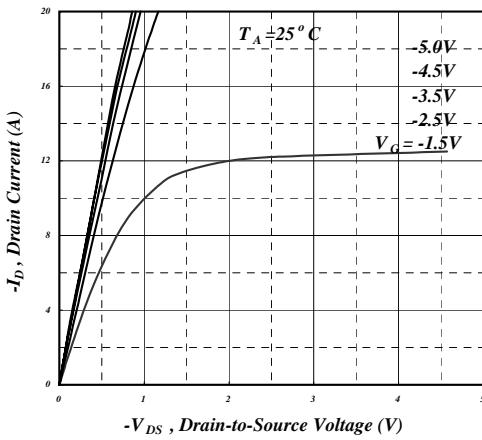


Fig 1. Typical Output Characteristics

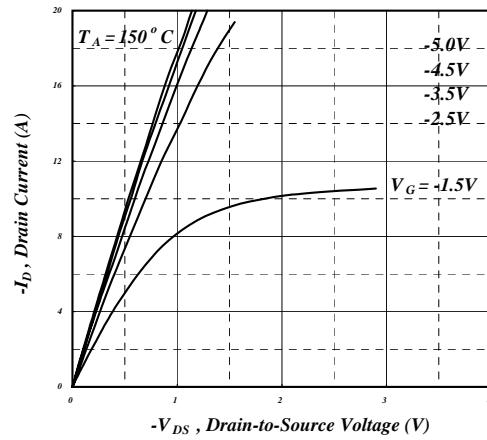


Fig 2. Typical Output Characteristics

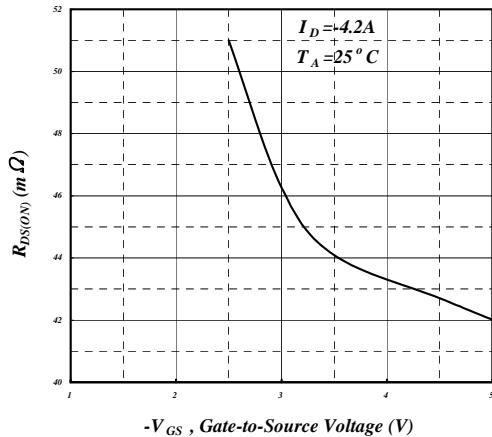


Fig 3. On-Resistance v.s. Gate Voltage

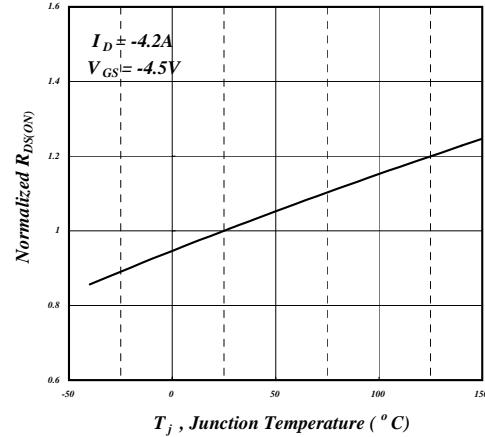


Fig 4. Normalized On-Resistance v.s. Junction Temperature

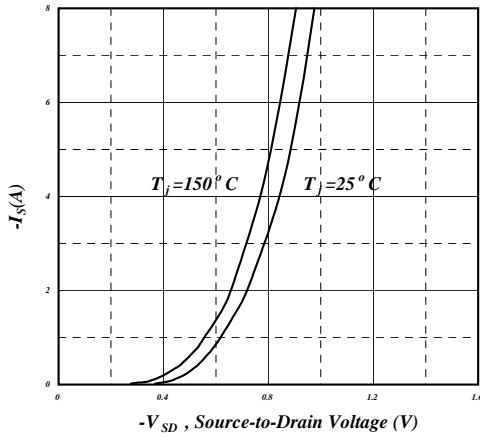


Fig 5. Forward Characteristic of Reverse Diode

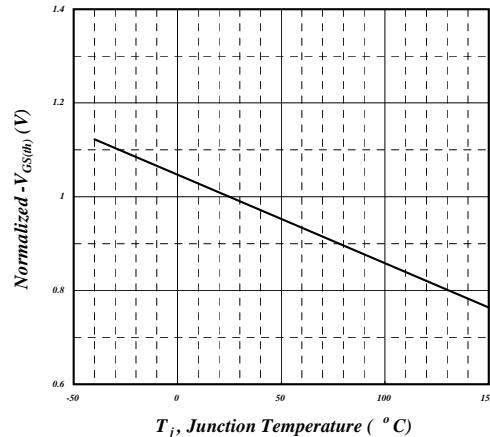


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

